

Notice of References Cited			Application/Control No. 08/636,069	Applicant(s)/Patent Under Reexamination SANDHU ET AL.	
			Examiner Erik Kielin	Art Unit 2813	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,579,750	04-1986	Bowen et al.	427/586
	B	US-4,581,248	04-1986	Roche, Gregory A.	427/554
	C	US-4,694,777	09-1987	Roche, Gregory A.	118/725
	D	US-4,782,787	11-1988	Roche, Gregory A.	118/722
	E	US-5,112,647	05-1992	Takabayashi, Akiharu	427/515
	F	US-5,605,867	02-1997	Sato et al.	438/790
	G	US-3,866,083	02-1975	Datta et al.	313/487
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 62077474 A	04-1987	Japan	TAKAMIYA, HIROSHI	C23C 16/48
	O	JP 05186875 A	07-1993	Japan	INOUE et al.	C23C 16/48
	P	JP 06104181 A	04-1994	Japan	WATANABE, TETSUO	H01L 21/205
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Harrison, The Cassell Dictionary of Physics, Cassell: London, 1988, pp. 44-45.
	V	Ohring, The Material Science of Thin Films, Academic Press: Boston, 1992, p. 53.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.